

March 2015

# FDD86102LZ

# N-Channel Shielded Gate PowerTrench<sup>®</sup> MOSFET 100 V, 35 A, 22.5 m $\Omega$

#### **Features**

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)}$  = 22.5 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 8 A
- Max  $r_{DS(on)}$  = 31 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 7 A
- HBM ESD protection level > 6 kV typical (Note 4)
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL tested
- RoHS Compliant

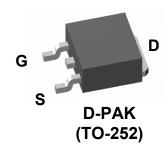


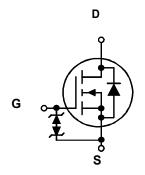
## **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and switching loss. G-S zener has been added to enhance ESD voltage level.

## **Applications**

- DC DC Conversion
- Inverter
- Synchronous Rectifier





### MOSFET Maximum Ratings T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			100	V
V <sub>GS</sub>	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C		35	
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	8	Α
	-Pulsed			40	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	84	mJ
D	Power Dissipation	T <sub>C</sub> = 25 °C		54	w
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	3.1	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	40	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD86102LZ	FDD86102LZ	D-PAK(TO-252)	13 "	16 mm	2500 units

# **Electrical Characteristics** $T_J$ = 25 $^{\circ}$ C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C		69		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μА

#### On Characteristics (Note 2)

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.5	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-6		mV/°C
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8 A		17.8	22.5	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 7 \text{ A}$		23.2	31	mΩ
, ,		$V_{GS}$ = 10 V, $I_{D}$ = 8 A, $T_{J}$ = 125 °C		31.1	40	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 8 A		31		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 50VV 0V	1157	1540	pF
Coss	Output Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz	181	245	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1 WH12	7.7	15	pF
R <sub>a</sub>	Gate Resistance		0.6		Ω

#### **Switching Characteristics**

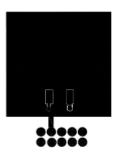
t <sub>d(on)</sub>	Turn-On Delay Time		6.6	14	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 8 A,	2.3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	20	32	ns
t <sub>f</sub>	Fall Time		2.3	10	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	18	26	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V} V_{DD} = 50 \text{ V},$	8.7	13	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	I <sub>D</sub> = 8 A	2.7		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		2.4		nC

#### **Drain-Source Diode Characteristics**

V <sub>SD</sub> Source to Drain Diode Forward V	Source to Drain Diode, Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 8 \text{ A}$ (Not	e 2)	0.82	1.3	V
	Source to Drain blode 1 of ward voltage	$V_{GS} = 0 \text{ V}, I_S = 2.6 \text{ A}$ (Not	e 2)	0.75	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 8 A, di/dt = 100 A/μs		43	70	ns
Q <sub>rr</sub>	Reverse Recovery Charge	- 1 <sub>F</sub> = 6 A, α//αι = 100 A/μs		43	70	nC

#### Notes:

 $R_{0JC}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{0JC}$  is guaranteed by design while  $R_{0JA}$  is determined by the user's board design.



a. 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



 b. 96 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.

<sup>3.</sup> Starting  $T_J$  = 25°C, L = 1 mH,  $I_{AS}$  = 13 A,  $V_{DD}$  = 90 V,  $V_{GS}$  = 10 V.

<sup>4.</sup> The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

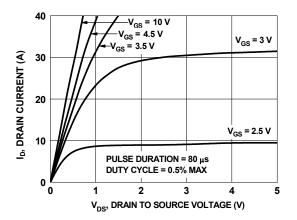


Figure 1. On-Region Characteristics

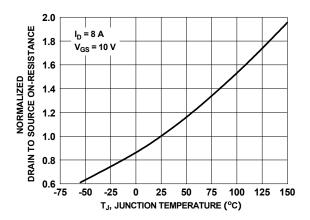


Figure 3. Normalized On-Resistance vs Junction Temperature

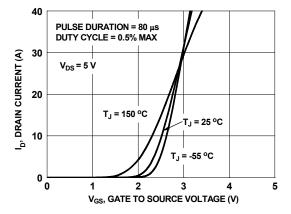


Figure 5. Transfer Characteristics

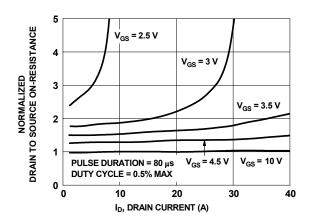


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

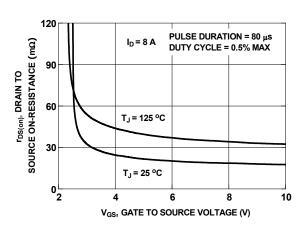


Figure 4. On-Resistance vs Gate to Source Voltage

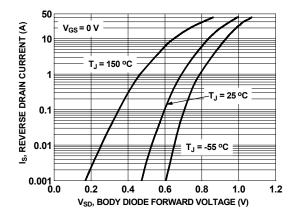


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J$ = 25 $^{\circ}$ C unless otherwise noted

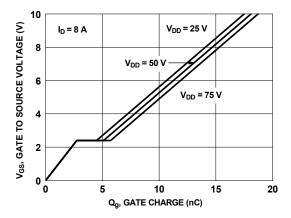


Figure 7. Gate Charge Characteristics

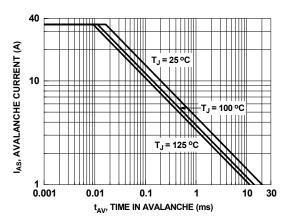


Figure 9. Unclamped Inductive Switching Capability

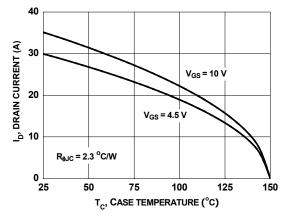


Figure 11. Maximum Continuous Drain Current vs Case Temperature

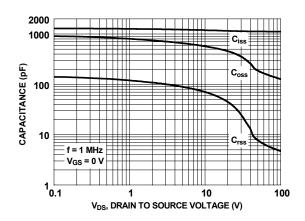


Figure 8. Capacitance vs Drain to Source Voltage

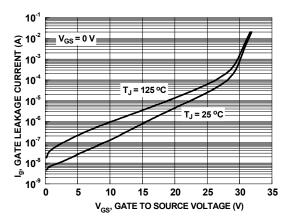


Figure 10. Gate Leakage Current vs Gate to Source Voltage

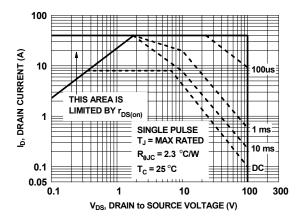


Figure 12. Forward BiasSafe Operating Area

# Typical Characteristics $T_J = 25$ °C unless otherwise noted

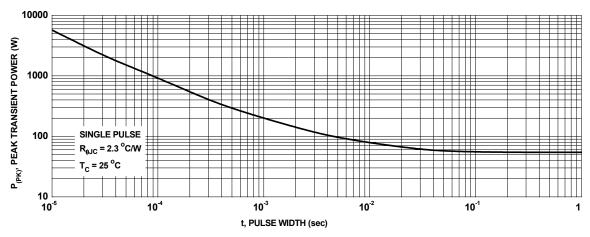


Figure 13. Single Pulse Maximum Power Dissipation

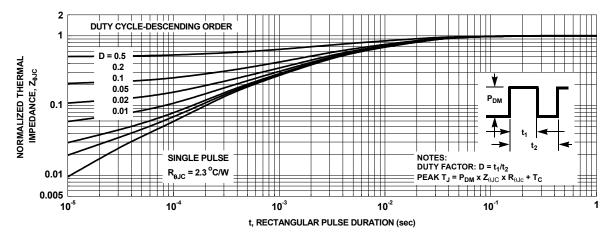
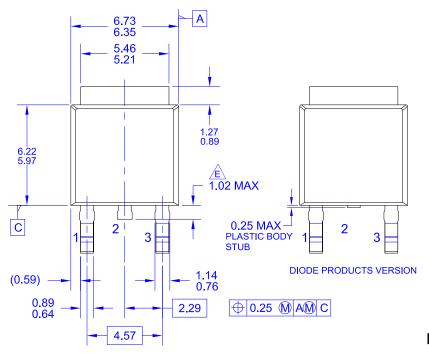
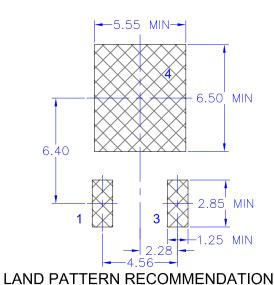
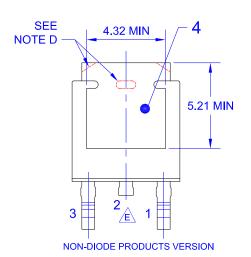


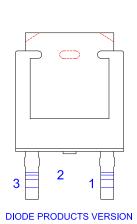
Figure 14. Junction-to-Case Transient Thermal Response Curve

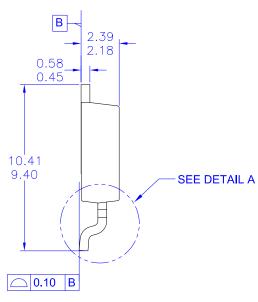




NON-DIODE PRODUCTS VERSION



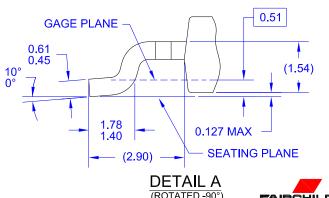




NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE CONFORMS TO JEDEC, TO-252,
- ISSUE C, VARIATION AA.

  B) ALL DIMENSIONS ARE IN MILLIMETERS.
  C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
- D) SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED CORNERS OR EDGE PROTRUSION.
- E) TRIMMED CENTER LEAD IS PRESENT ONLY FOR DIODE PRODUCTS
- F) DIMENSIONS ARE EXCLUSSIVE OF BURSS,
- MOLD FLASH AND TIE BAR EXTRUSIONS.
- G) LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD TO228P991X239-3N.
- H) DRAWING NUMBER AND REVISION: MKT-TO252A03REV10



(ROTATED -90°) SCALE: 12X







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beninder of Terms					
Datasheet Identification	Product Status	Definition			
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.			
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.			
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Rev. 174

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